Signetics

74AC/ACT11656

Octal Buffer/Line Driver with 9-Bit Parity Checker/Generator (3-State)

Objective Specification

ACL Products

FEATURES

- **3-State outputs**
- **Combines '244 and '280 functions in one package**
- **Output capability: ±24 mA**
- **CMOS (AC) and TTL (ACT) voltage level inputs**
- **50Ω incident wave switching**
- **Center-pin V_{CC} and ground configuration to minimize high-speed switching noise**
- **I_{CC} category: MSI**

DESCRIPTION

The 74AC/ACT11656 high-performance CMOS devices combine very high speed and high output drive comparable to the most advanced TTL families.

The 74AC/ACT11656 device is an octal buffer and line driver with parity generator/checker designed for use with memory address drivers, clock drivers, and bus-oriented transmitters/receivers.

GENERAL INFORMATION

SYMBOL	PARAMETER	CONDITIONS T_A = 25°C; GND = 0V; V_{CC} = 5.0V		TYPICAL AC	TYPICAL ACT	UNIT
t_{PLH}/ t_{PHL}	Propagation delay D_n to Q_n	C_L = 50pF		4.4	5.6	ns
C_{PD}	Power dissipation capacitance per buffer[1]	f = 1MHz; C_L = 50pF	Enabled	22	23	pF
			Disabled	8	8	
C_{IN}	Input capacitance	V_I = 0V or V_{CC}		4.5	4.5	pF
C_{OUT}	Output capacitance	V_O = 0V or V_{CC}; Disabled		10	10	pF
I_{LATCH}	Latch-up current	Per Jedec JC40.2 Standard 17		500	500	mA

Note:

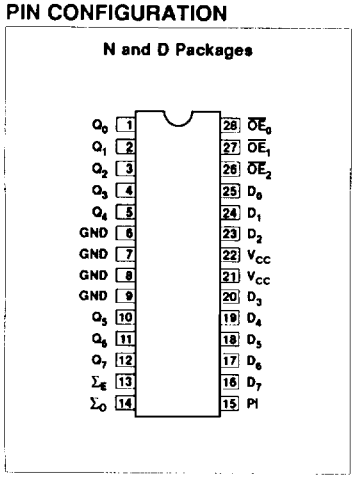
1. C_{PD} is used to determine the dynamic power dissipation (P_D in µW):
   $P_D = C_{PD} \times V_{CC}^2 \times f_I + \Sigma (C_L \times V_{CC}^2 \times f_O)$ where:
   f_I = input frequency in MHz, C_L = output load capacitance in pF,
   f_O = output frequency in MHz, V_{CC} = supply voltage in V,
   $\Sigma (C_L \times V_{CC}^2 \times f_O)$ = sum of outputs

ORDERING INFORMATION

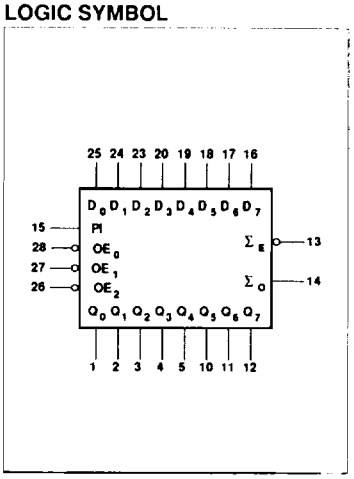
PACKAGES	TEMPERATURE RANGE	ORDER CODE
28-pin plastic DIP (300mil-wide)	-40°C to +85°C	74AC11656N 74ACT11656N
28-pin plastic SO (300mil-wide)	-40°C to +85°C	74AC11656D 74ACT11656D

PIN CONFIGURATION

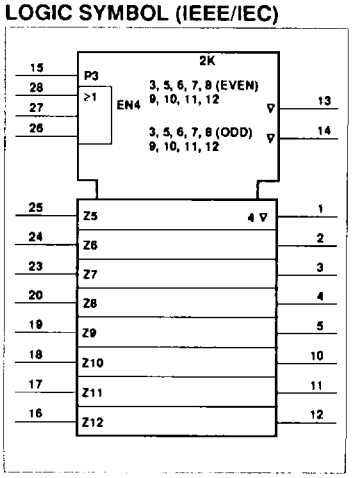
N and D Packages



LOGIC SYMBOL



LOGIC SYMBOL (IEEE/IEC)



PIN DESCRIPTION

PIN NUMBER	SYMBOL	NAME AND FUNCTION
15	PI	Parity input
28, 27, 26	$\overline{OE}_0$, $\overline{OE}_1$, $\overline{OE}_2$	Output enable input (active-Low)
25, 24, 23, 20, 19, 18, 17, 16	D_0 - D_7	Data inputs
1, 2, 3, 4, 5, 10, 11, 12	Q_0 - Q_7	Data outputs
13, 14	Σ_E, Σ_O	Parity outputs
6, 7, 8, 9	GND	Ground (0V)
21, 22	V_{CC}	Positive supply voltage

FUNCTION TABLE

INPUTS				OUTPUTS
$\overline{OE}_0$	$\overline{OE}_1$	$\overline{OE}_2$	D_n	Q_n
L	L	L	L	L
L	L	L	H	H
H	X	X	X	Z
X	H	X	X	Z
X	X	H	X	Z

H = High voltage level
L = Low voltage level
X = Don't care
Z = High-impedance state

INPUTS	PARITY OUTPUTS	
Number of inputs High (PI, D_0 - D_7)	Σ_E	Σ_O
EVEN—0, 2, 4, 6, 8	H	L
ODD—1, 3, 5, 7, 9	L	H
Any $\overline{OE}$ = High	Z	Z

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	74AC11656			74ACT11656			UNIT
		Min	Nom	Max	Min	Nom	Max	
V_{CC}	DC supply voltage	3.0[1]	5.0	5.5	4.5	5.0	5.5	V
V_I	Input voltage	0		V_{CC}	0		V_{CC}	V
V_O	Output voltage	0		V_{CC}	0		V_{CC}	V
$\Delta t/\Delta v$	Input transition rise or fall rate	0		10	0		10	ns/V
T_A	Operating free-air temperature	-40		+85	-40		+85	°C

NOTE:

1. No electrical or switching characteristics are specified at V_{CC} < 3V. Operation between 2V and 3V is not recommended, but within that range, a device output will maintain a previously established logic state.

ABSOLUTE MAXIMUM RATINGS[1]

SYMBOL	PARAMETER	TEST CONDITIONS	RATING	UNIT
V_{CC}	DC supply voltage		-0.5 to+7.0	V
I_{IK} or V_I	DC input diode current[2]	$V_I < 0$	-20	mA
		$V_I > V_{CC}$	20	
	DC input voltage		-0.5 to V_{CC} +0.5	V
I_{OK} or V_O	DC output diode current[2]	$V_O < 0$	-50	mA
		$V_O > V_{CC}$	50	
	DC output voltage		-0.5 to V_{CC} +0.5	V
I_O	DC output source or sink current per output pin	V_O = 0 to V_{CC}	±50	mA
I_{CC} or I_{GND}	DC V_{CC} current		±250	mA
	DC ground current		±250	
T_{STG}	Storage temperature		-65 to 150	°C
P_{TOT}	Power dissipation per package Plastic DIP	Above 70°C derate linearly by 8mW/K	500	mW
	Power dissipation per package Plastic surface mount (SO)	Above 70°C derate linearly by 6mW/K	400	mW

NOTES:

1. Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
2. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

DC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITIONS		V_{CC}	74AC11656				74ACT11656				UNIT
					T_A = +25°C		T_A = -40°C to +85°C		T_A = +25°C		T_A = -40°C to +85°C		
				V	Min	Max	Min	Max	Min	Max	Min	Max	
V_{IH}	High-level input voltage			3.0	2.10		2.10						V
				4.5	3.15		15		2.0		2.0		
				5.5	3.85		3.85		2.0		2.0		
V_{IL}	Low-level input voltage			3.0		0.90		0.90					V
				4.5		1.35		1.35		0.8		0.8	
				5.5		1.65		1.65		0.8		0.8	
V_{OH}	High-level output voltage	V_I = V_{IL} or V_{IH}	I_{OH} = -50µA	3.0	2.9		2.9						V
				4.5	4.4		4.4		4.4		4.4		
				5.5	5.4		5.4		5.4		5.4		
			I_{OH} = -4mA	3.0	2.58		2.48						
			I_{OH} = -24mA	4.5	3.94		3.8		3.94		3.8		
				5.5	4.94		4.8		4.94		4.8		
			I_{OH} = -75mA[1]	5.5			3.85				3.85		
V_{OL}	Low-level output voltage	V_I = V_{IL} or V_{IH}	I_{OL} = 50µA	3.0		0.1		0.1					V
				4.5		0.1		0.1		0.1		0.1	
				5.5		0.1		0.1		0.1		0.1	
			I_{OL} = 12mA	3.0		0.36		0.44					
			I_{OL} = 24mA	4.5		0.36		0.44		0.36		0.44	
				5.5		0.36		0.44		0.36		0.44	
			I_{OL} = 75mA[1]	5.5				1.65				1.65	
I_I	Input leakage current	V_I = V_{CC} or GND		5.5		±0.1		±1.0		±0.1		±1.0	µA
I_{OZ}	3-State output off-state current	V_I = V_{IL} or V_{IH}, V_O = V_{CC} or GND		5.5		±0.5		±5.0		±0.5		±5.0	µA
I_{CC}	Quiescent supply current	V_I = V_{CC} or GND, I_O = 0		5.5		8.0		80		8.0		80	µA
ΔI_{CC}	Supply current, TTL inputs High[2]	One input at 3.4V, other inputs at V_{CC} or GND		5.5						0.9		1.0	mA

NOTES:
1. Not more than one output should be tested at a time, and the duration of the test should not exceed 10ms.
2. This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0V or V_{CC}.